TEXAS INSTRUMENTS
LM5110
JAJSBW4B – MAY 2004 – REVISED SEPTEMBER 2016

# LM5110 デュアル5A複合ゲート・ドライバ、負出力電圧対応

## 1 特長

- 2つのNチャネルMOSFETを独立して駆動
- CMOSとバイポーラの複合出力によって出力電流の変動を低減
- シンク5A、ソース3Aの電流能力
- 2つのチャネルを並列接続して駆動電流を2倍にすることが可能
- 互いに独立した入力(TTL互換)
- 短い伝搬時間(代表値25ns)
- 短い立ち上がり/立ち下がり時間(2nF負荷で14ns/12nsの立ち上がり/立ち下がり)
- 専用の入力グランド・ピン(IN_REF)による正負2電源または単一電源による動作
- $V_{CC}$～$V_{EE}$の出力スイング(入力グランド基準で負の電圧も可)
- デュアル非反転、デュアル反転、および組み合わせ構成に対応
- シャットダウン入力による低消費電力モード
- 電源レールの低電圧誤動作防止保護
- 業界標準のゲート・ドライバと互換性のあるピン配置
- パッケージ
  - SOIC-8
  - WSON-10 (4mm×4mm)

## 2 アプリケーション

- 同期整流器ゲート・ドライバ
- スイッチ・モード電源ゲート・ドライバ
- ソレノイドおよびモータ・ドライバ

## 3 概要

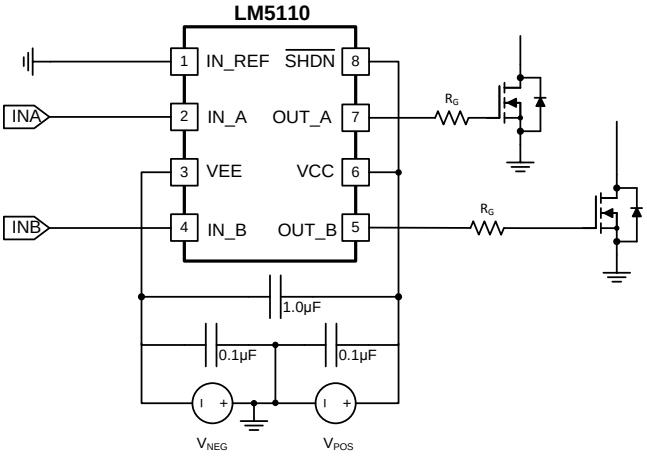
LM5110デュアル・ゲート・ドライバは、業界標準のゲート・ドライバと比較して、ピーク出力電流および効率が向上しています。“複合”出力ドライバの各ステージではMOSとバイポーラ・トランジスタが並列で動作し、容量性負荷から最大5Aのピーク電流をシンクします。MOSとバイポーラ・デバイスの固有の特性を組み合わせることで、電圧および温度による駆動電流の変動を低減します。入力と出力のグランド・ピンを個別に備えることで負電圧駆動が可能となり、正および負のVGS電圧でMOSFETのゲートを駆動できます。ゲート・ドライバ制御入力は、専用の入力グランド（IN_REF）を基準とします。ゲート・ドライバ出力のスイング範囲は$V_{CC}$から出力グランド$V_{EE}$までであり、VEEはIN_REFに対して負でもかまいません。。低電圧誤動作防止機能、およびシャットダウン入力ピンも搭載されています。入力および出力を互いに接続して2つのドライバを並列で動作させると、駆動電流を2倍にすることができます。このデバイスは、SOIC-8パッケージ、および熱特性を強化したWSON-10パッケージで供給されます。

**製品情報(1)**

| 型番 | パッケージ | 本体サイズ(公称) |
|---|---|---|
| LM5110 | SOIC (8) | 4.90mm×3.91mm |
| | WSON (10) | 4.00mm×4.00mm |

(1) 提供されているすべてのパッケージについては、巻末の注文情報を参照してください。

**アプリケーション概略図**

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## 4 改訂履歴

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

**Revision A (November 2012) から Revision B に変更** **Page**

- 「*ESD定格*」表、「*機能説明*」セクション、「*デバイスの機能モード*」セクション、「*アプリケーションと実装*」セクション、「*電源に関する推奨事項*」セクション、「*レイアウト*」セクション、「*デバイスおよびドキュメントのサポート*」セクション、「*メカニカル、パッケージ、および注文情報*」セクション 追加 ... 1
- Added *Thermal Information* table. ... 4


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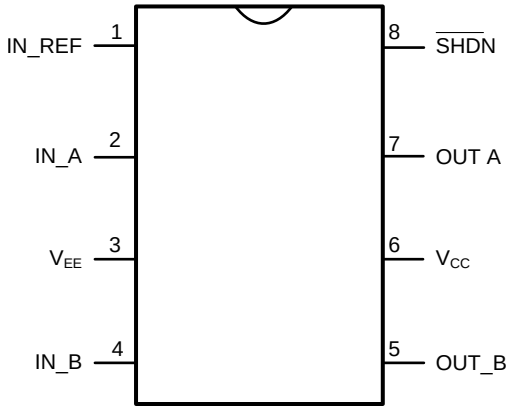
# 5 Device Options

**Table 1. Configuration Table**

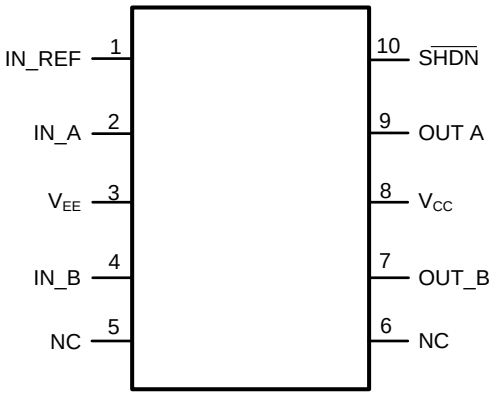
| PART NUMBER | "A" OUTPUT CONFIGURATION | "B" OUTPUT CONFIGURATION | PACKAGE |
|---|---|---|---|
| **LM5110-1M** | Noninverting | Noninverting | SOIC- 8 |
| **LM5110-2M** | Inverting | Inverting | SOIC- 8 |
| **LM5110-3M** | Inverting | Noninverting | SOIC- 8 |
| **LM5110-1SD** | Noninverting | Noninverting | WSON-10 |
| **LM5110-2SD** | Inverting | Inverting | WSON-10 |
| **LM5110-3SD** | Inverting | Noninverting | WSON-10 |

# 6 Pin Configuration and Functions

**D Package**
**8-Pin SOIC**
**Top View**




**DPR Package**
**10-Pin WSON**
**Top Pin**




**Pin Functions**

| PIN | | | I/O(1) | DESCRIPTION | APPLICATION INFORMATION |
|---|---|---|---|---|---|
| SOIC | WSON(2) | NAME | | | |
| 1 | 1 | IN_REF | G | Ground reference for control inputs | Connect to $V_{EE}$ for standard positive only output voltage swing. Connect to system logic ground reference for positive and negative output voltage swing. |
| 2 | 2 | IN_A | I | 'A' side control input | TTL compatible thresholds. |
| 3 | 3 | $V_{EE}$ | G | Power ground of the driver outputs | Connect to either power ground or a negative gate drive supply. |
| 4 | 4 | IN_B | I | 'B' side control input | TTL compatible thresholds. |
| 5 | 7 | OUT_B | O | Output for the 'B' side driver. | Capable of sourcing 3A and sinking 5A. Voltage swing of this output is from $V_{CC}$ to $V_{EE}$. |
| 6 | 8 | $V_{CC}$ | P | Positive supply | Locally decouple to $V_{EE}$ and IN_REF. |
| 7 | 9 | OUT_A. | O | Output for the 'A' side driver. | Capable of sourcing 3A and sinking 5A. Voltage swing of this output is from $V_{CC}$ to $V_{EE}$ . |
| 8 | 10 | nSHDN | I | Shutdown input pin | Pull below 1.5V to activate low power shutdown mode. |

(1) P = Power, G = Ground, I = Input, O = Output, I/O = Input/Output.
(2) Pins 5 and 6 are No Connect for WSON-10 packages.

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# 7 Specifications

## 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)(2)

| | MIN | MAX | UNIT |
|---|---|---|---|
| $V_{CC}$ to $V_{EE}$ | −0.3 | 15 | V |
| $V_{CC}$ to IN_REF | −0.3 | 15 | V |
| IN to IN_REF, nSHDN to IN_REF | −0.3 | 15 | V |
| IN_REF to $V_{EE}$ | −0.3 | 5 | V |
| Maximum junction temperature, ($T_J$(max)) | | 150 | °C |
| Operating junction temperature | | 125 | °C |
| Storage temperature, ($T_{stg}$) | –55 | 150 | °C |

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/ Distributors for availability and specifications.

## 7.2 ESD Ratings

| | | | VALUE | UNIT |
|---|---|---|---|---|
| $V_{(ESD)}$ | Electrostatic discharge | Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(1) | ±2000 | V |

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

## 7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

| | MIN | NOM | MAX | UNIT |
|---|---|---|---|---|
| $V_{CC}$ to $V_{EE}$ | 3.5 | - | 14 | V |
| $V_{CC}$ to IN_REF | 3.5 | - | 14 | V |
| IN_REF to $V_{EE}$ | 0 | | 4 | V |
| Junction Temperature | -40 | | 126 | °C |

## 7.4 Thermal Information

| THERMAL METRIC(1) | | LM5110 | | UNIT |
|---|---|---|---|---|
| | | D (SOIC) | DPR (WSON) | |
| | | 8 PINS | 10 PINS | |
| $R_{\theta JA}$ | Junction-to-ambient thermal resistance | 114 | 40.1 | °C/W |
| $R_{\theta JC(top)}$ | Junction-to-case (top) thermal resistance | 56.6 | 40.4 | °C/W |
| $R_{\theta JB}$ | Junction-to-board thermal resistance | 55.2 | 17.3 | °C/W |
| $\psi_{JT}$ | Junction-to-top characterization parameter | 10.3 | 0.5 | °C/W |
| $\psi_{JB}$ | Junction-to-board characterization parameter | 54.6 | 17.5 | °C/W |
| $R_{\theta JC(bot)}$ | Junction-to-case (bottom) thermal resistance | - | 6.3 | °C/W |

(1) For more information about traditional and new thermal metrics, see *Semiconductor and IC Package Thermal Metrics* application report.


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## 7.5 Electrical Characteristics

$T_J$ = −40°C to +125°C, $V_{CC}$ = 12V, $V_{EE}$ = IN_REF = 0V, nSHDN = $V_{CC}$, No Load on OUT_A or OUT_B, unless otherwise specified.

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---|---|---|---|---|---|---|
| | $V_{CC}$ Operating Range | $V_{CC}$−IN_REF and $V_{CC}$−$V_{EE}$ | 3.5 | | 14 | V |
| $V_{CCR}$ | $V_{CC}$ Under Voltage Lockout (rising) | $V_{CC}$−IN_REF | 2.3 | 2.9 | 3.5 | V |
| $V_{CCH}$ | $V_{CC}$ Under Voltage Lockout Hysteresis | | | 230 | | mV |
| $I_{CC}$ | $V_{CC}$ Supply Current ($I_{CC}$) | IN_A = IN_B = 0 V (5110-1) | | 1 | 2 | mA |
| | | IN_A = IN_B = $V_{CC}$ (5110-2) | | 1 | 2 | |
| | | IN_A = $V_{CC}$, IN_B = 0 V (5110-3) | | 1 | 2 | |
| $I_{CCSD}$ | $V_{CC}$ Shutdown Current ($I_{CC}$) | nSHDN = 0 V | | 18 | 25 | µA |
| **CONTROL INPUTS** | | | | | | |
| $V_{IH}$ | Logic High | | 2.2 | | | V |
| $V_{IL}$ | Logic Low | | | | 0.8 | V |
| HYS | Input Hysteresis | | | 400 | | mV |
| $I_{IL}$ | Input Current Low | IN_A=IN_B=$V_{CC}$ (5110-1-2-3) | −1 | 0.1 | 1 | µA |
| $I_{IH}$ | Input Current High | IN_A=IN_B=$V_{CC}$ (5110-1) | 10 | 18 | 25 | |
| | | IN_A=IN_B=$V_{CC}$ (5110-2) | −1 | 0.1 | 1 | |
| | | IN_A=$V_{CC}$ (5110-3) | –1 | 0.1 | 1 | |
| | | IN_B=$V_{CC}$ (5110-3) | 10 | 18 | 25 | |
| **SHUTDOWN INPUT** | | | | | | |
| ISD | Pullup Current | nSHDN = 0 V | | −18 | −25 | µA |
| VSDR | Shutdown Threshold | nSHDN rising | 0.8 | 1.5 | 2.2 | V |
| VSDH | Shutdown Hysteresis | | | 165 | | mV |
| **OUTPUT DRIVERS** | | | | | | |
| $R_{OH}$ | Output Resistance High | $I_{OUT}$ = −10 mA (1) | | 30 | 50 | Ω |
| $R_{OL}$ | Output Resistance Low | $I_{OUT}$ = + 10 mA (1) | | 1.4 | 2.5 | Ω |
| $I_{Source}$ | Peak Source Current | OUTA/OUTB = $V_{CC}$/2, 200 ns Pulsed Current | | 3 | | A |
| $I_{Sink}$ | Peak Sink Current | OUTA/OUTB = $V_{CC}$/2, 200 ns Pulsed Current | | 5 | | A |
| **LATCHUP PROTECTION** | | | | | | |
| | AEC - Q100, Method 004 | $T_J$ = 150°C | | 500 | | mA |

(1) The output resistance specification applies to the MOS device only. The total output current capability is the sum of the MOS and Bipolar devices.

## 7.6 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---|---|---|---|---|---|---|
| td1 | Propagation Delay Time Low to High, IN rising (IN to OUT) | $C_{LOAD}$ = 2 nF, see Figure 2 | | 25 | 40 | ns |
| td2 | Propagation Delay Time High to Low, IN falling (IN to OUT) | $C_{LOAD}$ = 2 nF, see Figure 2 | | 25 | 40 | ns |
| $t_r$ | Rise Time | $C_{LOAD}$ = 2 nF, see Figure 2 | | 14 | 25 | ns |
| $t_f$ | Fall Time | $C_{LOAD}$ = 2 nF, see Figure 2 | | 12 | 25 | ns |

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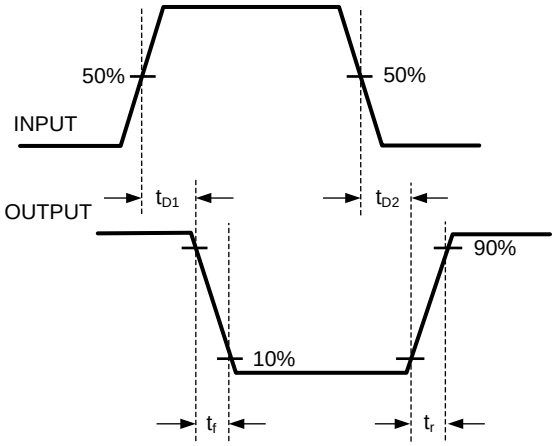
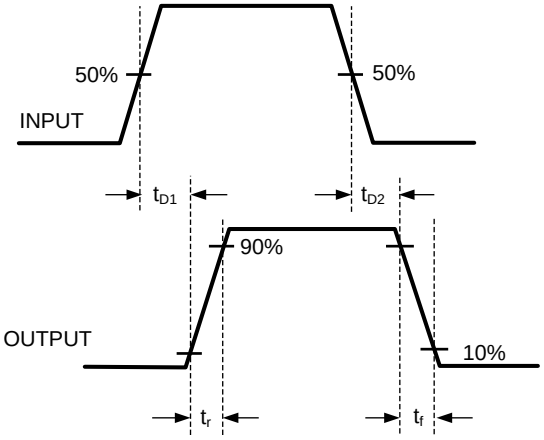



(a)

**Figure 1. Inverting**




(b)

**Figure 2. Noninverting**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## 7.7 Typical Characteristics

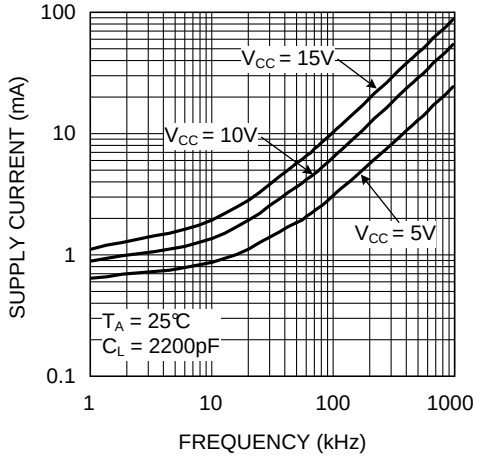


**Figure 3. Supply Current vs Frequency**

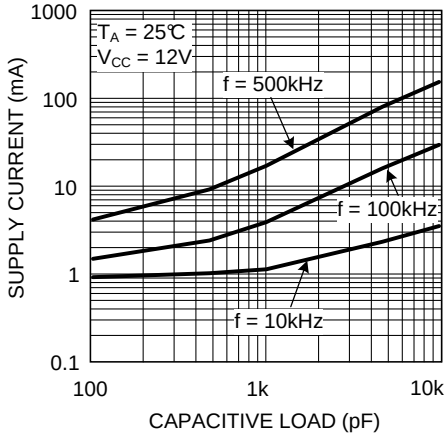


**Figure 4. Supply Current vs Load**

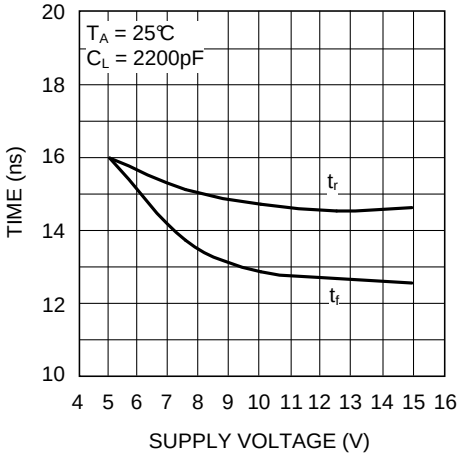


**Figure 5. Rise and Fall Time vs Supply Voltage**

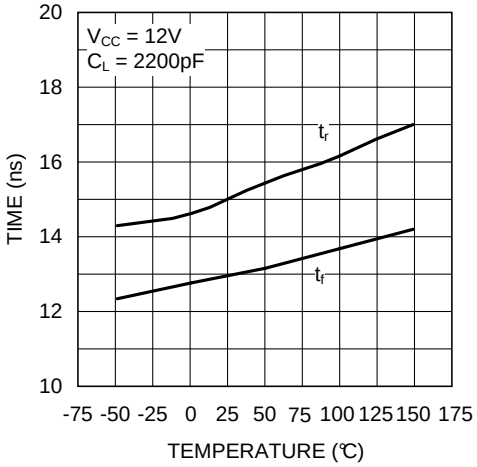


**Figure 6. Rise and Fall Time vs Temperature**

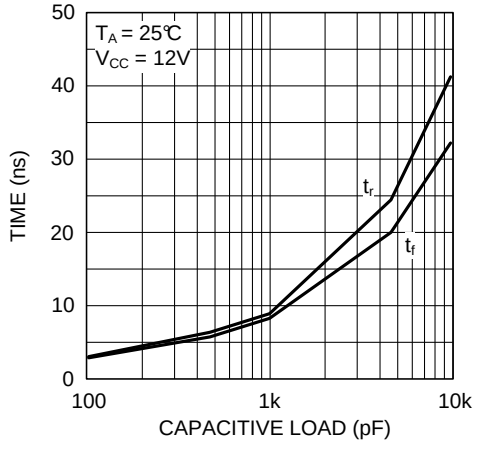


**Figure 7. Rise and Fall Time vs Capacitive Load**

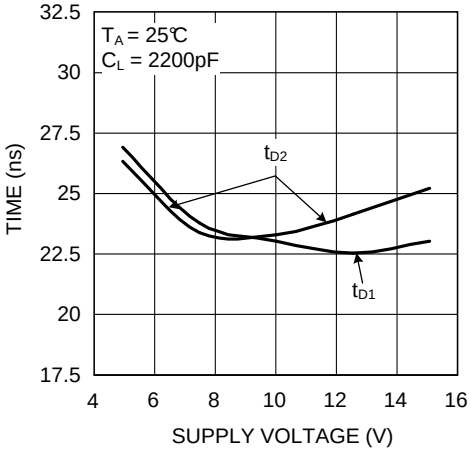


**Figure 8. Delay Time vs Supply Voltage**

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## Typical Characteristics (continued)

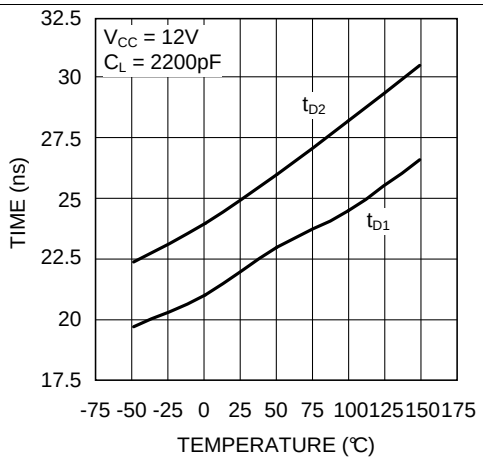


**Figure 9. Delay Time vs Temperature**

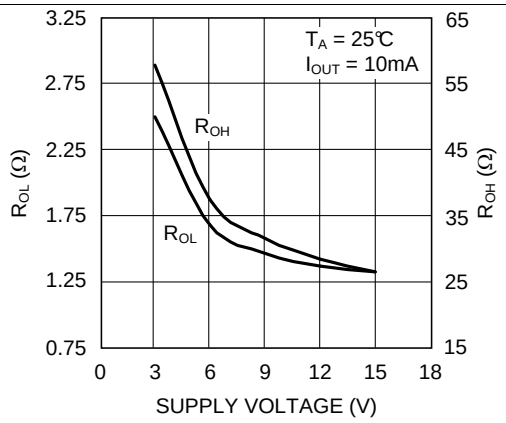


**Figure 10. $R_{DSON}$ vs Supply Voltage**

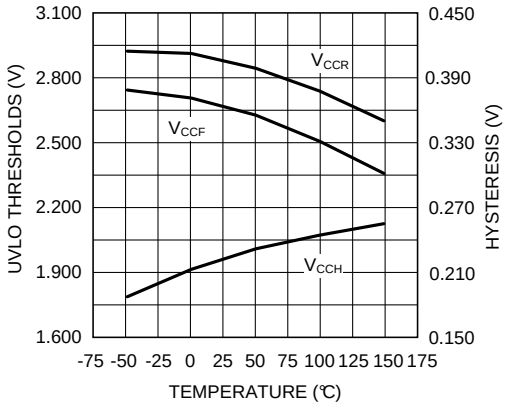


**Figure 11. UVLO Thresholds and Hysteresis vs Temperature**


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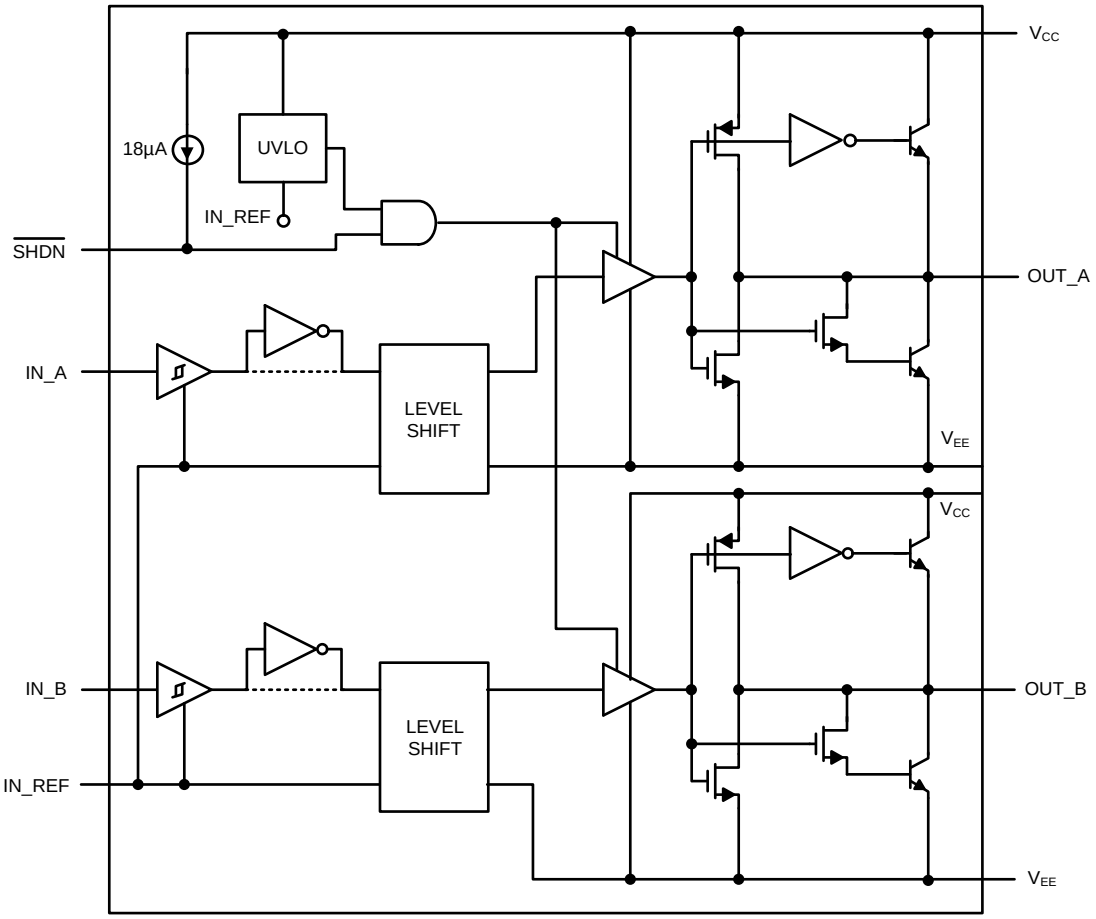
# 8 Detailed Description

## 8.1 Overview

LM5110 dual gate driver consists of two independent and identical driver channels with TTL compatible logic inputs and high current totem-pole outputs that source or sink current to drive MOSFET gates. The driver output consist of a compound structure with MOS and bipolar transistor operating in parallel to optimize current capability over a wide output voltage and operating temperature range. The bipolar device provides high peak current at the critical threshold region of the MOSFET VGS while the MOS devices provide rail-to-rail output swing. The totem pole output drives the MOSFET gate between the gate drive supply voltage $V_{CC}$ and the power ground potential at the $V_{EE}$ pin.

The LM5110 is available in dual noninverting (-1), dual inverting (-2) and the combination inverting plus noninverting (-3) configurations. All three configurations are offered in the SOIC-8 and WSON-10 plastic packages.

## 8.2 Functional Block Diagram

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## 8.3 Feature Description

### 8.3.1 Input Stage and Level Shifter

The control inputs of the drivers are high impedance CMOS buffers with TTL compatible threshold voltages. The negative supply of the input buffer is connected to the input ground pin IN_REF. An internal level shifting circuit connects the logic input buffers to the totem pole output drivers. The level shift circuit and separate input/output ground pins provide the option of single supply or split supply configurations. When driving MOSFET gates from a single positive supply, the IN_REF and $V_{EE}$ pins are both connected to the power ground. The LM5110 pinout was designed for compatibility with industry standard gate drivers in single supply gate driver applications. Pin 1 (IN_REF) on the LM5110 is a no-connect on standard driver IC's. Connecting pin 1 to pin 3 ($V_{EE}$) on the printed-circuit board accommodates the pin-out of both the LM5110 and competitive drivers.

The input stage of each driver should be driven by a signal with a short rise and fall time. Slow rising and falling input signals, although not harmful to the driver, may result in the output switching repeatedly at a high frequency.

The input pins of noninverting drivers have an internal 18-μA current source pull-down to IN-REF. The input pins of inverting driver channels have neither pullup nor pulldown current sources. Unused input should be tied to IN_REF or VCC and not left open.

### 8.3.2 Output Stage

The two driver channels of the LM5110 are designed as identical cells. Transistor matching inherent to integrated circuit manufacturing ensures that the AC and DC performance of the channels are nearly identical. Closely matched propagation delays allow the dual driver to be operated as a single driver if inputs and output pins are connected. The drive current capability in parallel operation is 2X the drive of either channel. Small differences in switching speed between the driver channels will produce a transient current (shoot-through) in the output stage when two output pins are connected to drive a single load. Differences in input thresholds between the driver channels will also produce a transient current (shoot-through) in the output stage. Fast transition input signals are especially important while operating in a parallel configuration. The efficiency loss for parallel operation has been characterized at various loads, supply voltages and operating frequencies. The power dissipation in the LM5110 increases by less than 1% relative to the dual driver configuration when operated as a single driver with inputs and outputs connected.

### 8.3.3 Turn-off with Negative Bias

The isolated input/output grounds provide the capability to drive the MOSFET to a negative VGS voltage for a more robust and reliable off state. In split supply configuration, the IN_REF pin is connected to the ground of the controller which drives the LM5110 inputs. The $V_{EE}$ pin is connected to a negative bias supply that can range from the IN-REF as much as 14-V below the $V_{CC}$ gate drive supply.

Enhancement mode MOSFETs do not inherently require a negative bias on the gate to turn off the FET. However, certain applications may benefit from the capability of negative VGS voltage during turnoff including:

1. When the gate voltages cannot be held safely below the threshold voltage due to transients or coupling in the printed-circuit-board.
2. When driving low threshold MOSFETs at high junction temperatures.
3. When high switching speeds produce capacitive gate-drain current that lifts the internal gate potential of the MOSFET.

### 8.3.4 UVLO and Power Supplies

An undervoltage lockout (UVLO) circuit is included in the LM5110, which senses the voltage difference between $V_{CC}$ and the input ground pin, IN_REF. When the $V_{CC}$ to IN_REF voltage difference falls below 2.7 V, both driver channels are disabled. The driver will resume normal operation when the $V_{CC}$ to IN_REF differential voltage exceeds approximately 2.9 V. UVLO hysteresis prevents chattering during brown-out conditions.

The maximum recommended voltage difference between $V_{CC}$ and IN_REF or between $V_{CC}$ and $V_{EE}$ is 14 V. The minimum voltage difference between $V_{CC}$ and IN_REF is 3.5 V.


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## Feature Description (continued)

### 8.3.5 Shutdown $\overline{\text{SHDN}}$

The Shutdown pin ($\overline{\text{SHDN}}$) is a TTL compatible logic input provided to enable/disable both driver channels. When $\overline{\text{SHDN}}$ is in the logic low state, the LM5110 is switched to a low power standby mode with total supply current less than 25 µA. This function can be effectively used for start-up, thermal overload, or short circuit fault protection. TI recommends connecting this pin to $V_{CC}$ when the shutdown function is not being used. The shutdown pin has an internal 18-µA current source pullup to $V_{CC}$.

## 8.4 Device Functional Modes

The device operates in normal mode and UVLO mode. See Table 2 for more information on UVLO operation mode. In normal mode when the $V_{CC}$ and $V_{IN–REF}$ are above UVLO threshold, the output stage is dependent on the states of the IN_A, IN_B and nSHDN pins. The output HO and LO will be low if input state is floating.

**Table 2. INPUT/OUTPUT Logic Table**

| IN_A (1) | IN_B (1) | $\overline{\text{SHDN}}$ | OUT_A (2) | OUT_B (2) |
|---|---|---|---|---|
| L | L | H or Left Open | L | L |
| L | H | H or Left Open | L | H |
| H | L | H or Left Open | H | L |
| H | H | H or Left Open | H | H |
| X | X | L | L | L |

(1) IN_A and IN_B is referenced to IN_REF.
(2) OUT_A and OUT_B is referenced to VEE.

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# 9 Applications and Implementation

**NOTE**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 9.1 Application Information

To operate fast switching of power MOSFETs at high switching frequencies and to reduce associated switching losses, a powerful gate driver is employed between the PWM output of controller and the gates of the power semiconductor devices. Also, gate drivers are indispensable when it is impossible for the PWM controller to directly drive the gates of the switching devices. With the advent of digital power, this situation is often encountered because the PWM signal from the digital controller is often a 3.3 V logic signal which cannot effectively turn on a power switch. Level shift circuit is needed to boost the 3.3 V signal to the gate-drive voltage (such as 12 V) in order to fully turn-on the power device and minimize conduction losses. Traditional buffer drive circuits based on NPN/PNP bipolar transistors in totem-pole arrangement prove inadequate with digital power because they lack level-shifting capability. Gate drivers effectively combine both the level-shifting and buffer-drive functions. Gate drivers also find other needs such as minimizing the effect of high-frequency switching noise (by placing the high-current driver IC physically close to the power switch), driving gate-drive transformers and controlling floating power-device gates, reducing power dissipation and thermal stress in controllers by moving gate charge power losses from the controller into the driver.

The LM5110 Dual Gate Driver replaces industry standard gate drivers with improved peak output current and efficiency. Each "compound" output driver stage includes MOS and bipolar transistors operating in parallel that together sink more than 5A peak from capacitive loads. Combining the unique characteristics of MOS and bipolar devices reduces drive current variation with voltage and temperature. Separate input and output ground pins provide Negative Drive Capability allowing the user to drive MOSFET gates with positive and negative VGS voltages.


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## 9.2 Typical Application

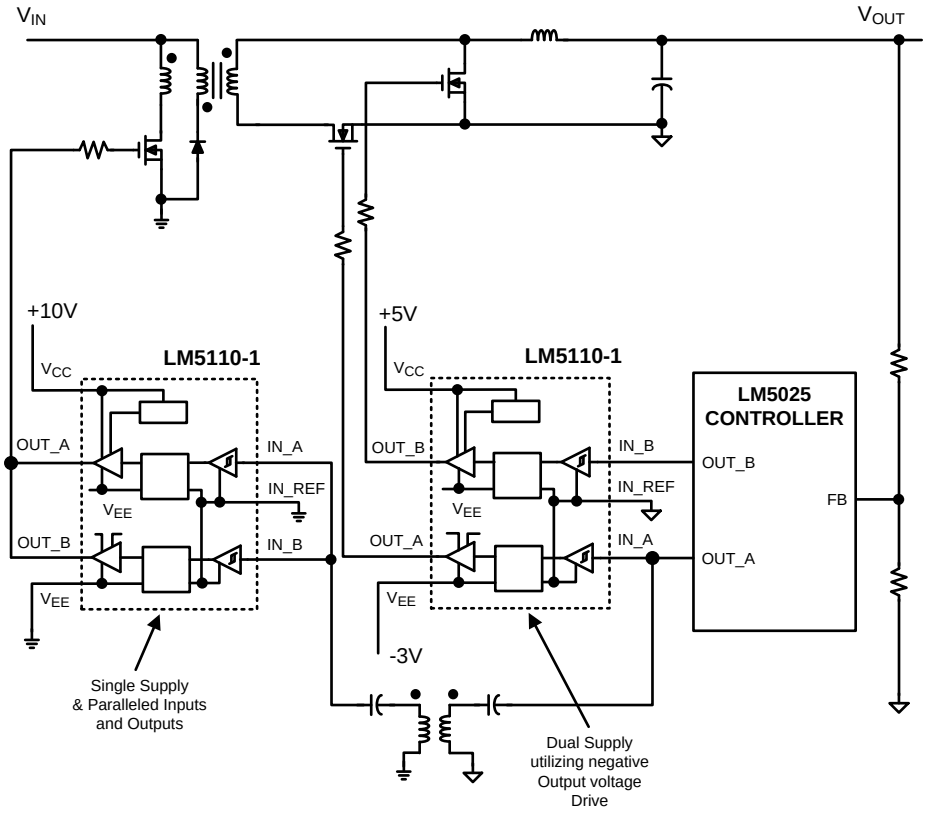


**Figure 12. Simplified Power Converter Using Synchronous Rectifiers With Negative Off Gate Voltage**

### 9.2.1 Design Requirements

To select proper device from LM5110 family, TI recommends first checking the appropriate logic for the outputs. LM5110-2 has dual inverting outputs; LM5110-1 has dual noninverting outputs; LM5110-3 have inverting channel A and noninverting channel B. Moreover, some design considerations must be evaluated first in order to make the most appropriate selection. Among these considerations are VCC, drive current, and power dissipation.

### 9.2.2 Detailed Design Procedure

#### *9.2.2.1 Parallel Outputs*

The A and B drivers may be combined into a single driver by connecting the INA/INB inputs together as close to the IC as possible, and the OUTA/OUTB outputs ties together if the external gate drive resistor is not used. In some cases where the external gate drive resistor is used, TI recommends that the resistor can be equally split in OUTA and OUTB respectively to reduce the parasitic inductance induce unbalance between two channels, as show in Figure 13.

## Typical Application (continued)

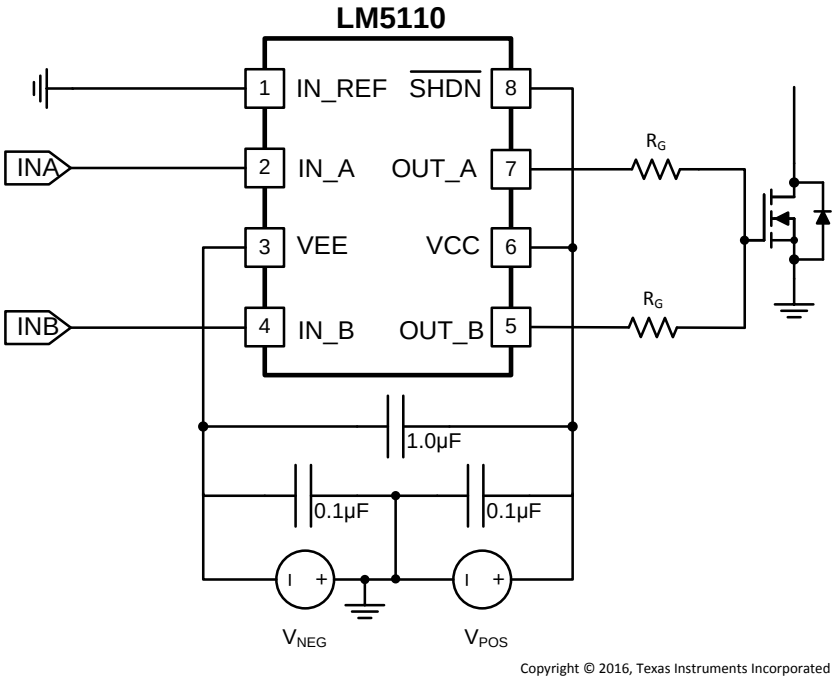


**Figure 13. Parallel Operation of LM5110-1 and LM5110-2**

Important consideration about paralleling two channels for LM5110 include: 1) IN_A and IN_B should be shorted in PCB layout as close to the device as possible, as well as for OUT_A and OUT_B, in which condition PCB layout parasitic mismatching between two channels could be minimized. 2) INA/B input slope signal should be fast enough to avoid mismatched $V_{IH}/V_{IL}$, $t_{d1}/t_{d2}$ between channel-A and channel-B. TI recommends having input signal slope faster than 20 V/µs.

### 9.2.3 Application Curves

Figure 14 and Figure 15 shows the total operation current comsumption vs load and frequency.

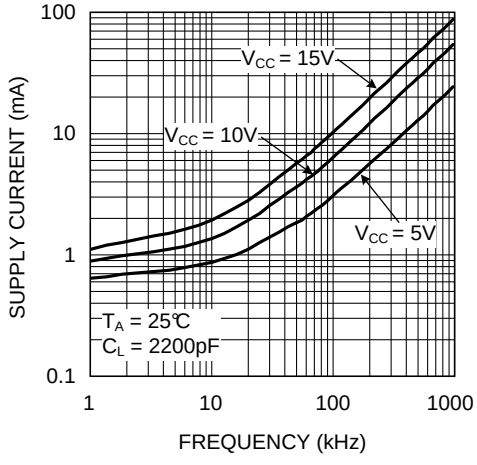


**Figure 14. Operating Current vs Switching Frequency**

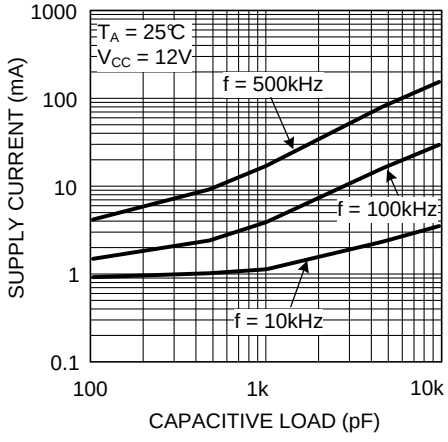


**Figure 15. Operating Current vs Load Capacitance**


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# 10 Power Supply Recommendations

The recommended bias supply voltage range for LM5110 is from 3.5 V to 14 V. The upper end of this range is driven by the 15 V absolute maximum voltage rating of the VCC. TI recommends keeping proper margin to allow for transient voltage spikes.

A local bypass capacitor must be placed between the VCC and IN_REF pins, as well as between the VCC and VEE. This capacitor must be placed as close to the device as possible. A low ESR, ceramic surface mount capacitor is recommended. TI recommends using 2 capacitors in parallel: a 100-nF ceramic surface-mount capacitor for high frequency filtering placed as close to VCC as possible, and another surface-mount capacitor, 220 nF to 10 µF, for IC bias requirements.

# 11 Layout

## 11.1 Layout Guidelines

Attention must be given to board layout when using LM5110. Some important considerations include:

1. A Low ESR/ESL capacitor must be connected close to the IC and between the $V_{CC}$ and $V_{EE}$ pins to support high peak currents being drawn from $V_{CC}$ during turn-on of the MOSFET.
2. Proper grounding is crucial. The drivers need a very low impedance path for current return to ground avoiding inductive loops. The two paths for returning current to ground are a) between LM5110 IN-REF pin and the ground of the circuit that controls the driver inputs, b) between LM5110 $V_{EE}$ pin and the source of the power MOSFET being driven. All these paths should be as short as possible to reduce inductance and be as wide as possible to reduce resistance. All these ground paths should be kept distinctly separate to avoid coupling between the high current output paths and the logic signals that drive the LM5110. A good method is to dedicate one copper plane in a multi-layered PCB to provide a common ground surface.
3. With the rise and fall times in the range of 10 ns to 30 ns, care is required to minimize the lengths of current carrying conductors to reduce their inductance and EMI from the high di/dt transients generated by the LM5110.
4. The LM5110 SOIC footprint is compatible with other industry standard drivers. Simply connect IN_REF pin of the LM5110 to $V_{EE}$ (pin 1 to pin 3) to operate the LM5110 in a standard single supply configuration.
5. If either channel is not being used, the respective input pin (IN_A or IN_B) should be connected to either IN_REF or $V_{CC}$ to avoid spurious output signals. If the shutdown feature is not used, the nSHDN pin should be connected to $V_{CC}$ to avoid erratic behavior that would result if system noise were coupled into a floating 'nSHDN' pin.

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## 11.2 Layout Example

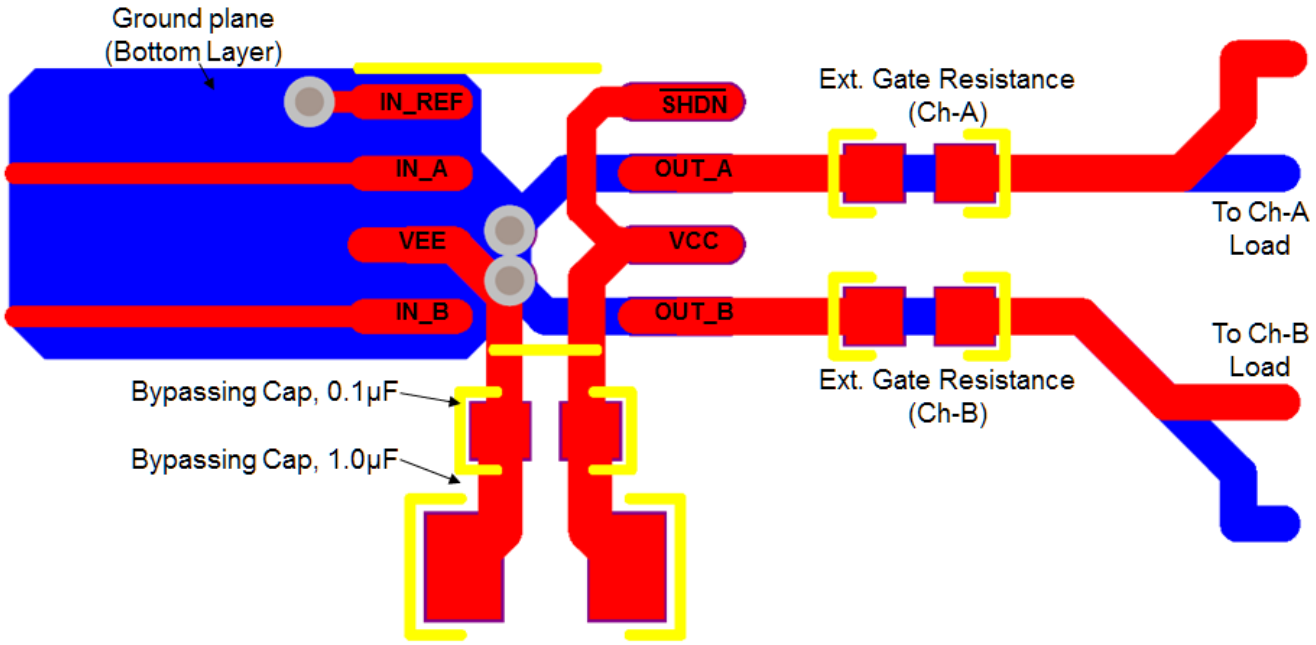


**Figure 16. SOIC(8) Layout Example**

## 11.3 Thermal Considerations

The primary goal of thermal management is to maintain the integrated circuit (IC) junction temperature ($T_J$) below a specified maximum operating temperature to ensure reliability. It is essential to estimate the maximum $T_J$ of IC components in worst case operating conditions. The junction temperature is estimated based on the power dissipated in the IC and the junction to ambient thermal resistance $\theta_{JA}$ for the IC package in the application board and environment. The $\theta_{JA}$ is not a given constant for the package and depends on the printed circuit board design and the operating environment.

### 11.3.1 Drive Power Requirement Calculations in LM5110

The LM5110 dual low side MOSFET driver is capable of sourcing/sinking 3-A/5-A peak currents for short intervals to drive a MOSFET without exceeding package power dissipation limits. High peak currents are required to switch the MOSFET gate very quickly for operation at high frequencies.

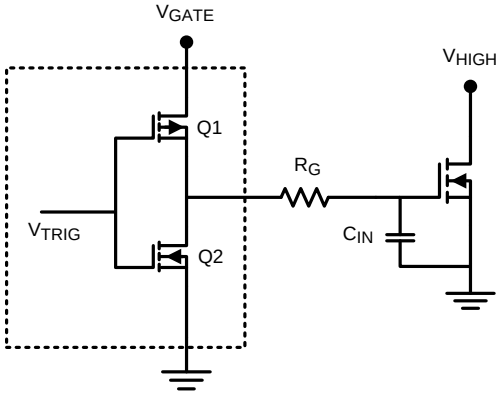


**Figure 17. LM5110 drives MOSFET with Driver Output Stage and MOSFET Gate-Source Capacitance**


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## Thermal Considerations (continued)

The schematic above shows a conceptual diagram of the LM5110 output and MOSFET load. Q1 and Q2 are the switches within the gate driver. $R_G$ is the gate resistance of the external MOSFET, and $C_{IN}$ is the equivalent gate capacitance of the MOSFET. The gate resistance Rg is usually very small and losses in it can be neglected. The equivalent gate capacitance is a difficult parameter to measure since it is the combination of $C_{GS}$ (gate to source capacitance) and $C_{GD}$ (gate to drain capacitance). Both of these MOSFET capacitances are not constants and vary with the gate and drain voltage. The better way of quantifying gate capacitance is the total gate charge $Q_G$ in coloumbs. $Q_G$ combines the charge required by $C_{GS}$ and $C_{GD}$ for a given gate drive voltage $V_{GATE}$.

Assuming negligible gate resistance, the total power dissipated in the MOSFET driver due to gate charge is approximated by

$$P_{DRIVER} = V_{GATE} \times Q_G \times F_{SW}$$

where

- $F_{SW}$ = switching frequency of the MOSFET (1)

As an example, consider the MOSFET MTD6N15 whose gate charge specified as 30 nC for $V_{GATE}$ = 12 V.

The power dissipation in the driver due to charging and discharging of MOSFET gate capacitances at switching frequency of 300 kHz and $V_{GATE}$ of 12 V is equal to

$$P_{DRIVER} = 12\ V \times 30\ nC \times 300\ kHz = 0.108\ W. \quad (2)$$

If both channels of the LM5110 are operating at equal frequency with equivalent loads, the total losses will be twice as this value which is 0.216 W.

In addition to the above gate charge power dissipation, - transient power is dissipated in the driver during output transitions. When either output of the LM5110 changes state, current will flow from $V_{CC}$ to $V_{EE}$ for a very brief interval of time through the output totem-pole N and P channel MOSFETs. The final component of power dissipation in the driver is the power associated with the quiescent bias current consumed by the driver input stage and undervoltage lockout sections.

Characterization of the LM5110 provides accurate estimates of the transient and quiescent power dissipation components. At 300-kHz switching frequency and 30-nC load used in the example, the transient power will be 8 mW. The 1-mA nominal quiescent current and 12-V $V_{GATE}$ supply produce a 12-mW typical quiescent power.

Therefore the total power dissipation

$$P_D = 0.216 + 0.008 + 0.012 = 0.236W. \quad (3)$$

We know that the junction temperature is given by

$$T_J = P_D \times \theta_{JA} + T_A \quad (4)$$

Or the rise in temperature is given by

$$T_{RISE} = T_J - T_A = P_D \times \theta_{JA} \quad (5)$$

For SOIC-8 package $\theta_{JA}$ is estimated as 114°C/W see *Thermal Information* section.

Therefore $T_{RISE}$ is equal to

$$T_{RISE} = 0.236 \times 114 \approx 27°C \quad (6)$$

For WSON-10 package, the integrated circuit die is attached to leadframe die pad which is soldered directly to the printed circuit board. This substantially decreases the junction to ambient thermal resistance ($\theta_{JA}$). $\theta_{JA}$ as low as 40°C/W is achievable with the WSON10 package. The resulting $T_{RISE}$ for the dual driver example above is thereby reduced to just 9.5°.

### 11.3.2 Continuous Current Rating of LM5110

The LM5110 can deliver pulsed source/sink currents of 3 A and 5 A to capacitive loads. In applications requiring continuous load current (resistive or inductive loads), package power dissipation, limits the LM5110 current capability far below the 5-A sink/3-A source capability. Rated continuous current can be estimated both when sourcing current to or sinking current from the load. For example when sinking, the maximum sink current can be calculated using Equation 7.

$$I_{SINK}(MAX) := \sqrt{\frac{T_J(MAX) - T_A}{\theta_{JA} \cdot R_{DS}(ON)}}$$

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## Thermal Considerations (continued)

where

- $R_{DS}$(on) is the on resistance of lower MOSFET in the output stage of LM5110. (7)

Consider $T_J$(max) of 125°C and $\theta_{JA}$ of 114°C/W for an SO-8 package under the condition of natural convection and no air flow. If the ambient temperature ($T_A$) is 60°C, and the $R_{DS}$(on) of the LM5110 output at $T_J$(max) is 2.5 Ω, this equation yields $I_{SINK}$(max) of 478 mA which is much smaller than 5-A peak pulsed currents.

Similarly, the maximum continuous source current can be calculated as

$$I_{SOURCE}(MAX) := \frac{T_J(MAX) - T_A}{\theta_{JA} \cdot V_{DIODE}}$$

where

- $V_{DIODE}$ is the voltage drop across hybrid output stage which varies over temperature and can be assumed to be about 1.1 V at $T_J$(max) of 125°C (8)

Assuming the same parameters as above, this equation yields $I_{SOURCE}$(max) of 518 mA.


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# 12 デバイスおよびドキュメントのサポート

## 12.1 ドキュメントの更新通知を受け取る方法

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## 12.2 コミュニティ・リソース

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

**TI E2E™ Online Community** ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

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## 12.5 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

# 13 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスについて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

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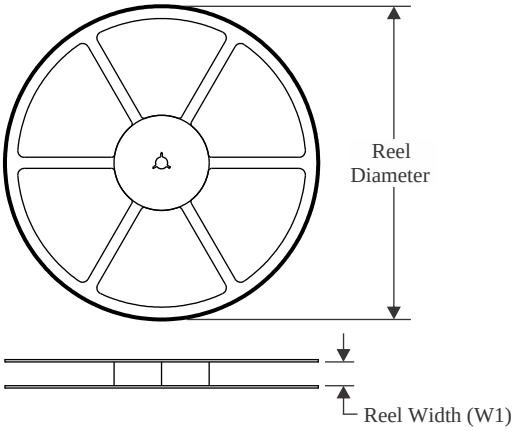
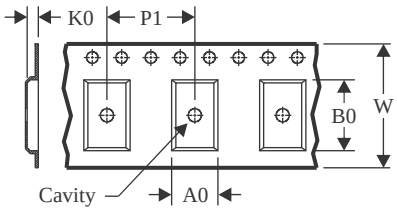
## TAPE AND REEL INFORMATION

**REEL DIMENSIONS**

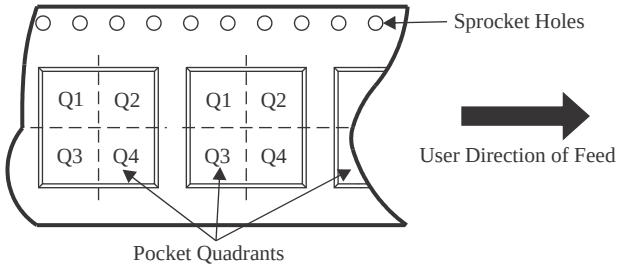



**TAPE DIMENSIONS**




| | |
|---|---|
| A0 | Dimension designed to accommodate the component width |
| B0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

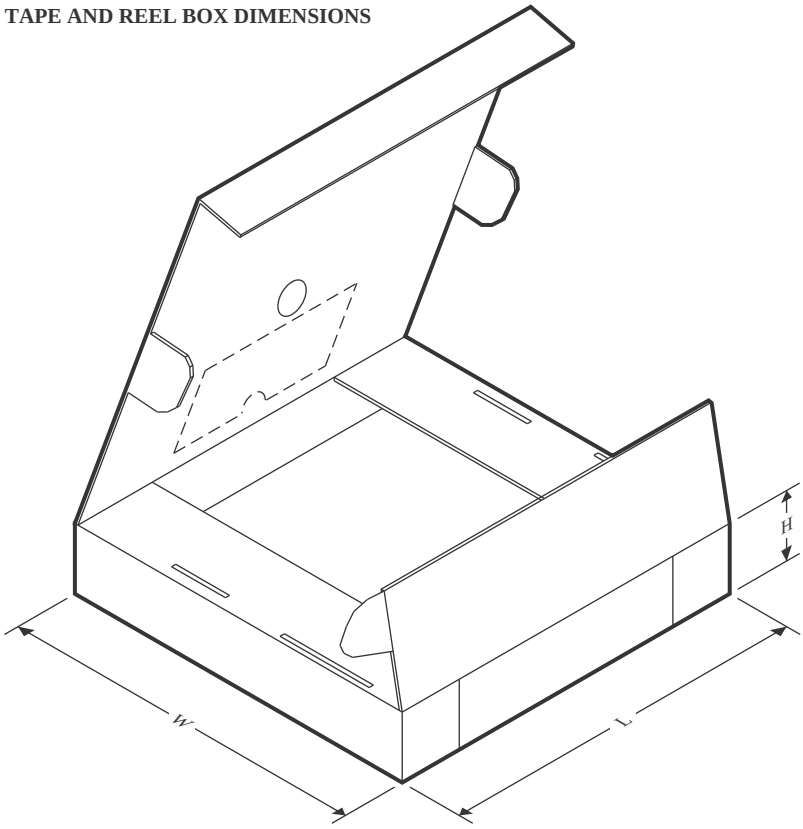
**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**




*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|---|---|---|---|---|---|---|---|---|---|---|---|---|
| LM5110-1MX/NOPB | SOIC | D | 8 | 2500 | 330.0 | 12.4 | 6.5 | 5.4 | 2.0 | 8.0 | 12.0 | Q1 |
| LM5110-1SD | WSON | DPR | 10 | 1000 | 178.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |
| LM5110-1SD/NOPB | WSON | DPR | 10 | 1000 | 178.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |
| LM5110-1SDX/NOPB | WSON | DPR | 10 | 4500 | 330.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |
| LM5110-2MX/NOPB | SOIC | D | 8 | 2500 | 330.0 | 12.4 | 6.5 | 5.4 | 2.0 | 8.0 | 12.0 | Q1 |
| LM5110-2SD/NOPB | WSON | DPR | 10 | 1000 | 178.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |
| LM5110-3MX/NOPB | SOIC | D | 8 | 2500 | 330.0 | 12.4 | 6.5 | 5.4 | 2.0 | 8.0 | 12.0 | Q1 |
| LM5110-3SD/NOPB | WSON | DPR | 10 | 1000 | 178.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |
| LM5110-3SDX/NOPB | WSON | DPR | 10 | 4500 | 330.0 | 12.4 | 4.3 | 4.3 | 1.3 | 8.0 | 12.0 | Q1 |

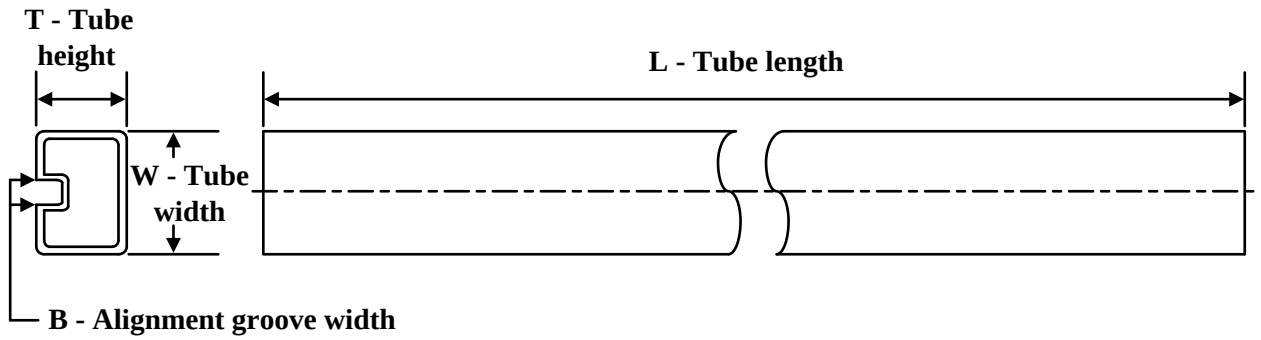
TAPE AND REEL BOX DIMENSIONS




*All dimensions are nominal

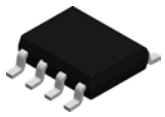
| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|---|---|---|---|---|---|---|---|
| LM5110-1MX/NOPB | SOIC | D | 8 | 2500 | 367.0 | 367.0 | 35.0 |
| LM5110-1SD | WSON | DPR | 10 | 1000 | 208.0 | 191.0 | 35.0 |
| LM5110-1SD/NOPB | WSON | DPR | 10 | 1000 | 208.0 | 191.0 | 35.0 |
| LM5110-1SDX/NOPB | WSON | DPR | 10 | 4500 | 367.0 | 367.0 | 35.0 |
| LM5110-2MX/NOPB | SOIC | D | 8 | 2500 | 367.0 | 367.0 | 35.0 |
| LM5110-2SD/NOPB | WSON | DPR | 10 | 1000 | 208.0 | 191.0 | 35.0 |
| LM5110-3MX/NOPB | SOIC | D | 8 | 2500 | 367.0 | 367.0 | 35.0 |
| LM5110-3SD/NOPB | WSON | DPR | 10 | 1000 | 208.0 | 191.0 | 35.0 |
| LM5110-3SDX/NOPB | WSON | DPR | 10 | 4500 | 367.0 | 367.0 | 35.0 |

## TUBE




*All dimensions are nominal

| Device | Package Name | Package Type | Pins | SPQ | L (mm) | W (mm) | T (µm) | B (mm) |
|---|---|---|---|---|---|---|---|---|
| LM5110-1M/NOPB | D | SOIC | 8 | 95 | 495 | 8 | 4064 | 3.05 |
| LM5110-1M/NOPB | D | SOIC | 8 | 95 | 495 | 8 | 4064 | 3.05 |
| LM5110-2M/NOPB | D | SOIC | 8 | 95 | 495 | 8 | 4064 | 3.05 |
| LM5110-3M/NOPB | D | SOIC | 8 | 95 | 495 | 8 | 4064 | 3.05 |

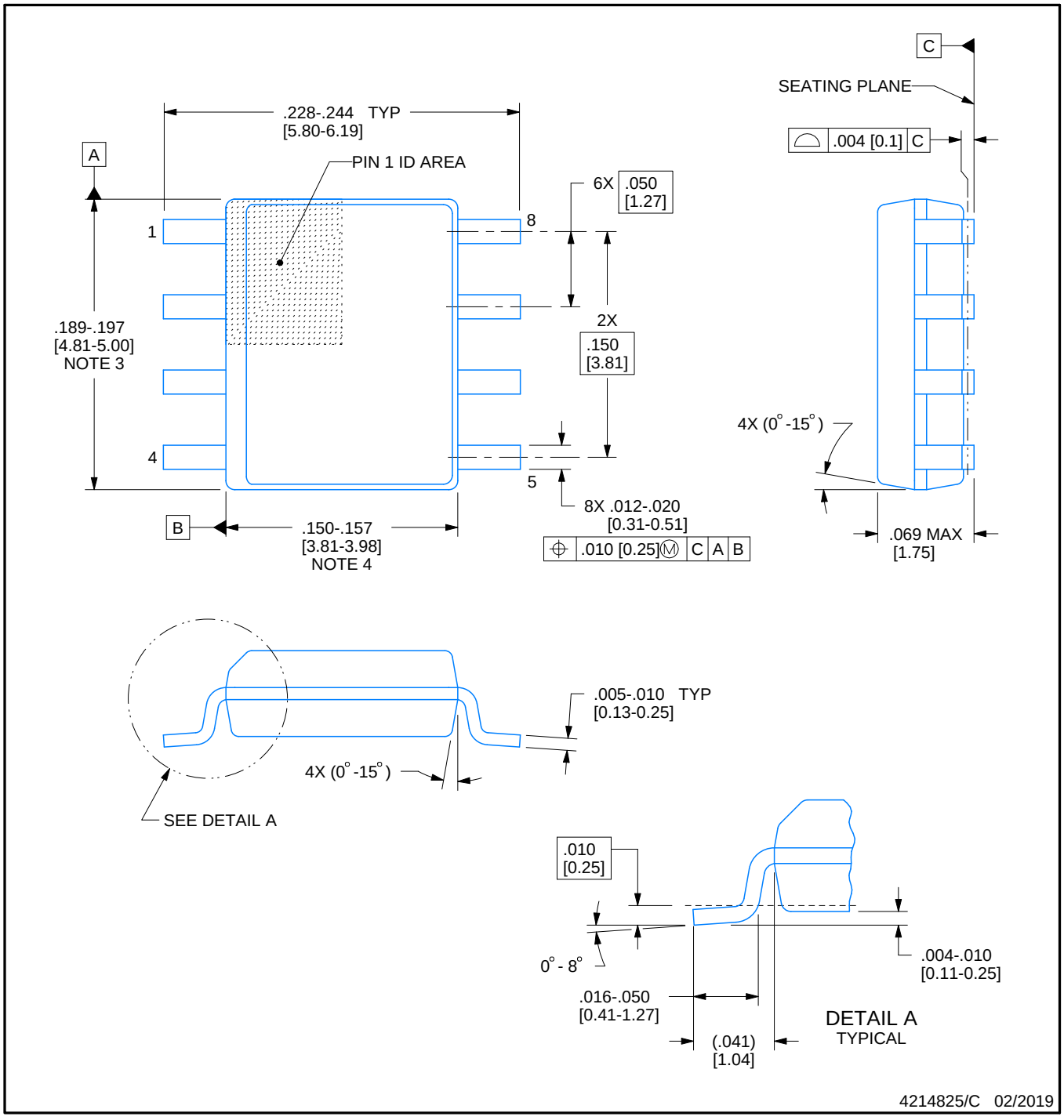


# PACKAGE OUTLINE

## D0008A

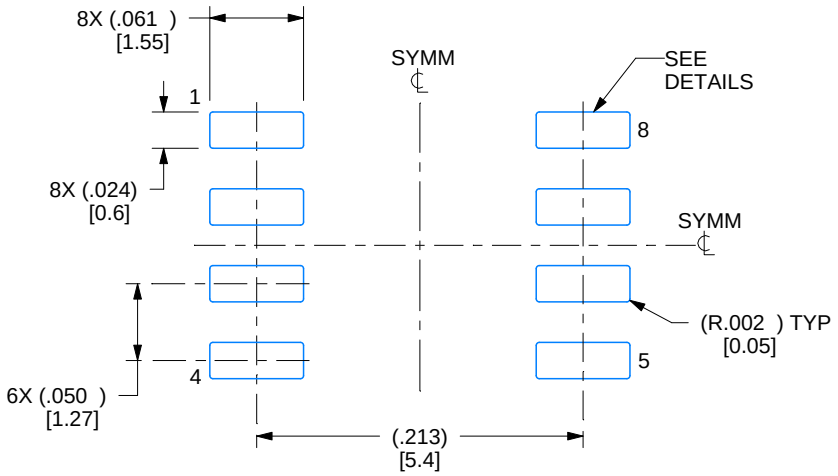
## SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

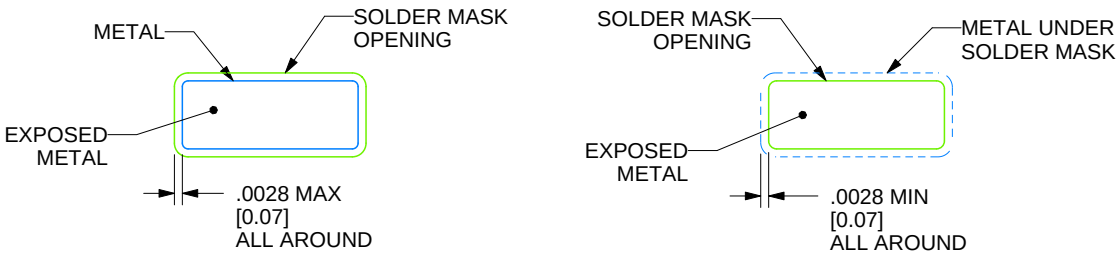



NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.




LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X




SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

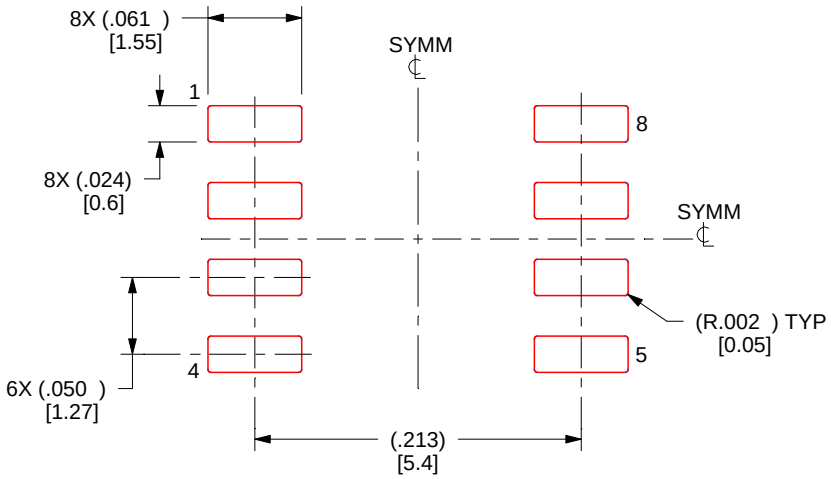
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

## D0008A

## SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT




SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

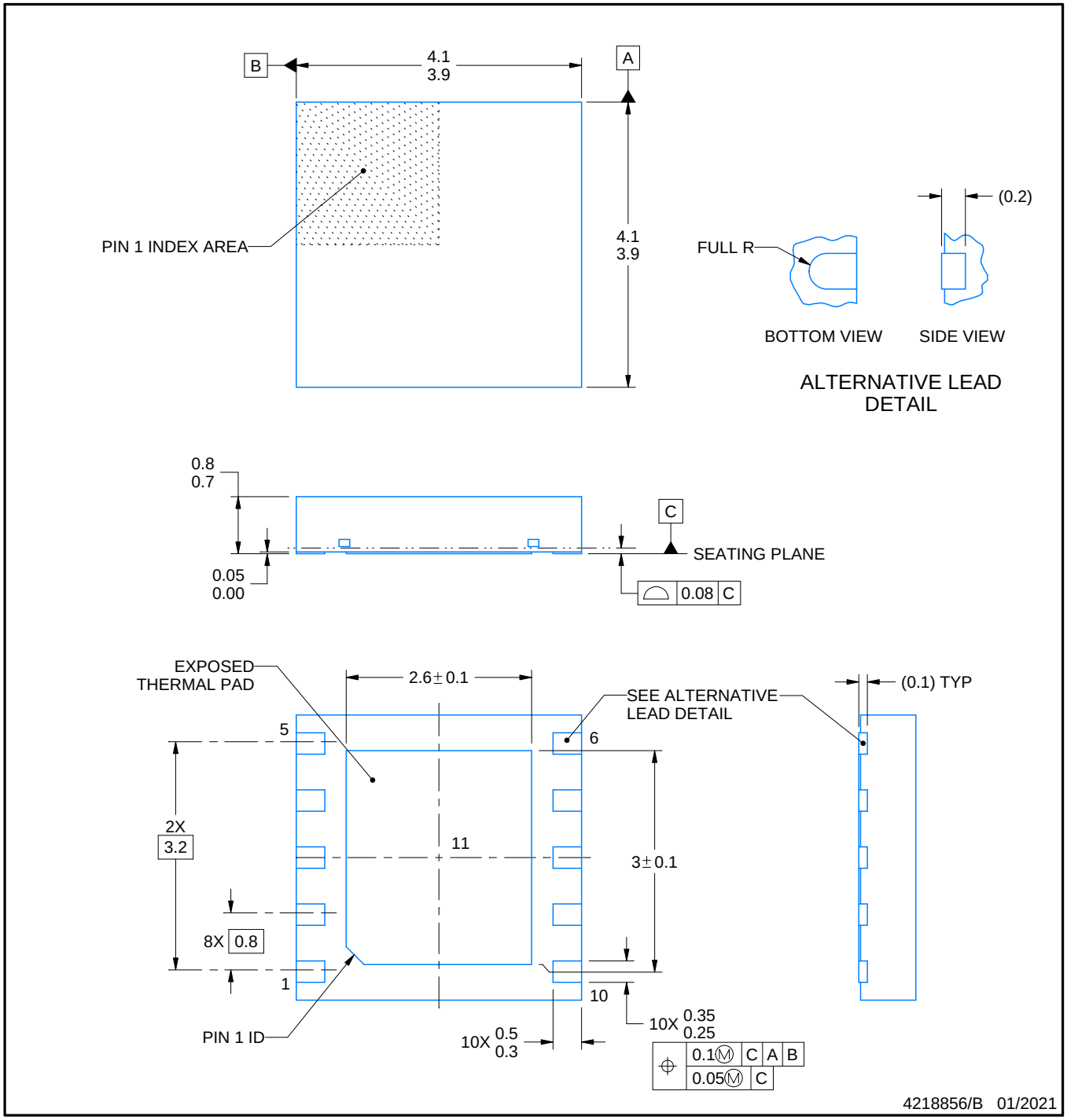
8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

# PACKAGE OUTLINE

## DPR0010A

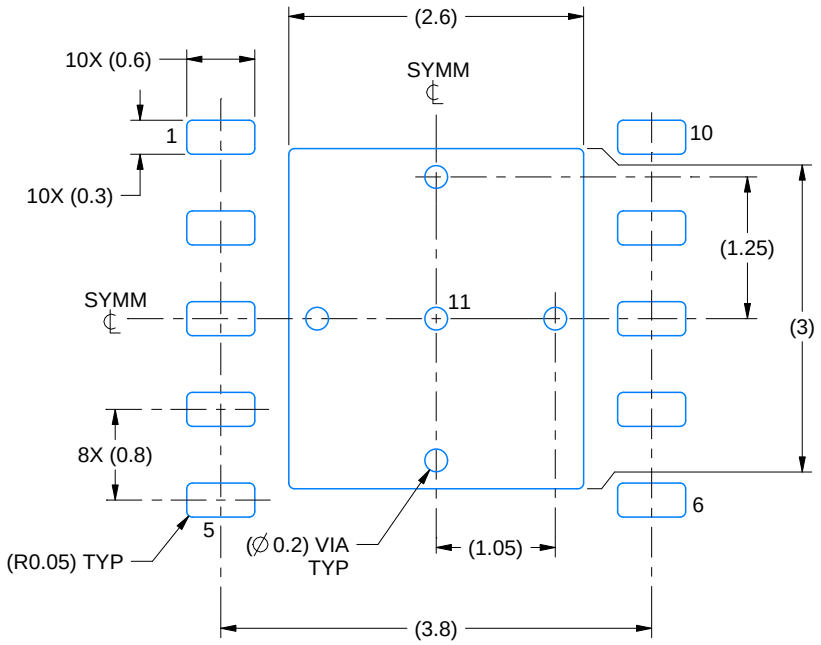
## WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD

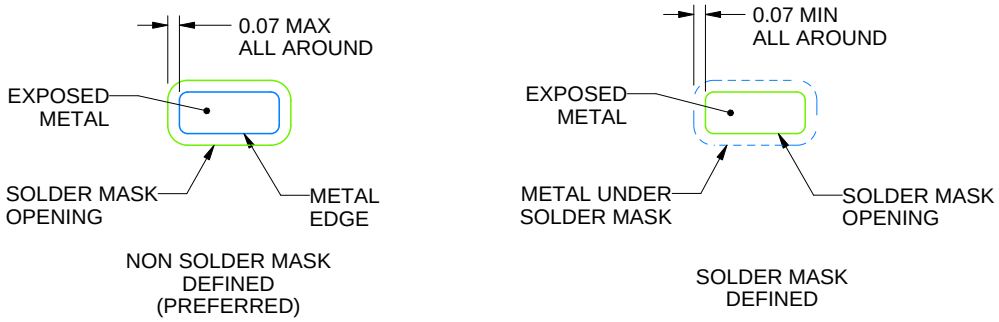



NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.




LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X

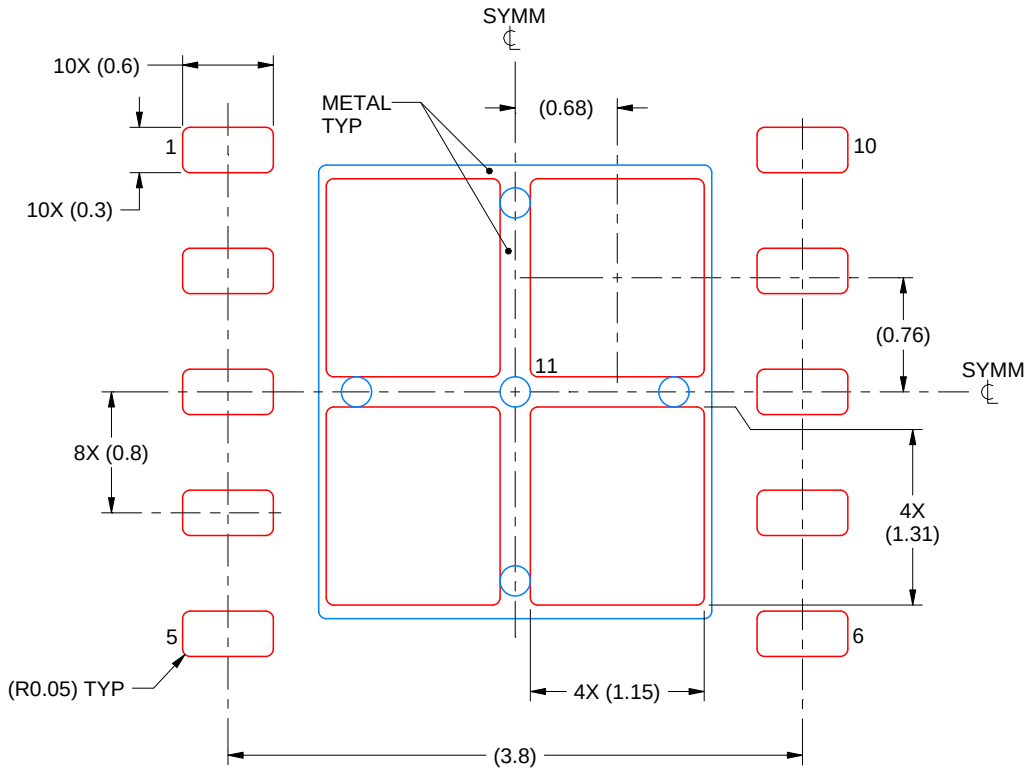



SOLDER MASK DETAILS

4218856/B 01/2021

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).




SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL

EXPOSED PAD 11:
77% PRINTED SOLDER COVERAGE BY AREA
SCALE:20X

4218856/B 01/2021

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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